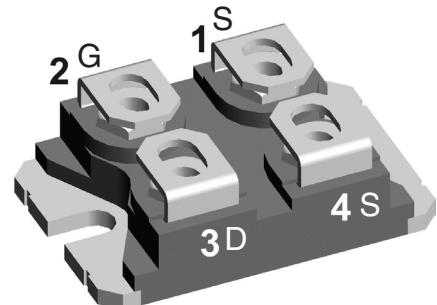


# SiC Power MOSFET

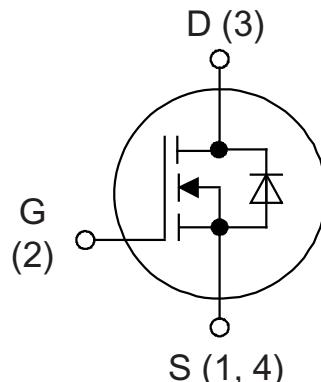
$I_{D25}$  = 47 A  
 $V_{DSS}$  = 1200 V  
 $R_{DS(on)\ max}$  = 50 mΩ

**Part number**  
**IXFN50N120SiC**



Backside: isolated

 E72873



## Features / Advantages:

- High speed switching with low capacitances
- High blocking voltage with low  $R_{DS(on)}$
- Easy to parallel and simple to drive
- Avalanche ruggedness
- Resistant to latch-up

## Applications:

- Solar inverters
- High voltage DC/DC converters
- Motor drives
- Switch mode power supplies
- UPS
- Battery chargers
- Induction heating

## Package:

- SOT-227B (minibloc)
- Isolation Voltage: 2500 V~
  - Industry standard outline
  - RoHS compliant
  - Epoxy meets UL 94V-0
  - Base plate with Aluminium nitride isolation
  - Advanced power cycling

## Disclaimer Notice

Information furnished is believed to be accurate and reliable. However, users should independently evaluate the suitability of and test each product selected for their own applications. Littelfuse products are not designed for, and may not be used in, all applications. Read complete Disclaimer Notice at [www.littelfuse.com/disclaimer-electronics](http://www.littelfuse.com/disclaimer-electronics).



## MOSFET

Symbol	Definitions	Conditions	Ratings		
			min.	typ.	max.
$V_{DSS}$	drain source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 200 \mu\text{A}$	1200		V
$V_{GSM}$	max transient gate source voltage		-10		+25 V
$V_{GS}$	continuous gate source voltage	recommended operational value	-5		+20 V
$I_{D25}$	drain current	$V_{GS} = 20 \text{ V}$	$T_C = 25^\circ\text{C}$		47 A
$I_{D80}$			$T_C = 80^\circ\text{C}$		35 A
$I_{D100}$			$T_C = 100^\circ\text{C}$		30 A
$I_{D(\text{pulse})}$	pulsed drain current	pulse width limited by $T_{VJ \text{ max}}$			125 A
$P_D$	power dissipation		$T_C = 25^\circ\text{C}, T_{VJ} = 175^\circ\text{C}$		270 W
$R_{DSon}$	static drain source on resistance	$I_D = 40 \text{ A}; V_{GS} = 20 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$	40	$\text{m}\Omega$
			$T_{VJ} = 150^\circ\text{C}$	75	$\text{m}\Omega$
$V_{GS(\text{th})}$	gate threshold voltage	$I_D = 10 \text{ mA}; V_{GS} = V_{DS}$	$T_{VJ} = 25^\circ\text{C}$	2.0	V
			$T_{VJ} = 150^\circ\text{C}$	2.1	V
$I_{DSS}$	drain source leakage current	$V_{DS} = 1200 \text{ V}; V_{GS} = 0 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$	2	$\mu\text{A}$
			$T_{VJ} = 150^\circ\text{C}$	20	$\mu\text{A}$
$I_{GSS}$	gate source leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$		0.5 $\mu\text{A}$
$R_G$	internal gate resistance				4.8 $\Omega$
$C_{iss}$	input capacitance	$V_{DS} = 1000 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$	$T_{VJ} = 25^\circ\text{C}$	1900	pF
$C_{oss}$	output capacitance			160	pF
$C_{rss}$	reverse transfer (Miller) capacitance			13	pF
$Q_g$	total gate charge	$V_{DS} = 800 \text{ V}; I_D = 40 \text{ A}; V_{GS} = 0/20 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$	100	nC
$Q_{gs}$	gate source charge			22	nC
$Q_{gd}$	gate drain (Miller) charge			36	nC
$t_{d(on)}$	turn-on delay time	$V_{DS} = 800 \text{ V}; I_D = 40 \text{ A}$ $V_{GS} = -5 / 20 \text{ V}; R_G = 10 \Omega$ (external) Freewheeling diode is Mosfet's body diode		23	ns
$t_r$	current rise time			9	ns
$t_{d(off)}$	turn-off delay time			75	ns
$t_f$	current fall time			19	ns
$E_{on}$	turn-on energy per pulse		$T_{VJ} = 25^\circ\text{C}$	1.08	mJ
$E_{off}$	turn-off energy per pulse			0.29	mJ
$E_{rec(off)}$	reverse recovery losses at turn-off			0.04	mJ
$t_{d(on)}$	turn-on delay time	$V_{DS} = 800 \text{ V}; I_D = 40 \text{ A}$ $V_{GS} = -5 / 20 \text{ V}; R_G = 10 \Omega$ (external) Freewheeling diode is Mosfet's body diode		23	ns
$t_r$	current rise time			9	ns
$t_{d(off)}$	turn-off delay time			100	ns
$t_f$	current fall time			22	ns
$E_{on}$	turn-on energy per pulse		$T_{VJ} = 150^\circ\text{C}$	1.48	mJ
$E_{off}$	turn-off energy per pulse			0.35	mJ
$E_{rec(off)}$	reverse recovery losses at turn-off			0.10	mJ
$R_{thJC}$	thermal resistance junction to case	with heatsink compound; IXYS test setup		0.55	K/W
$R_{thJH}$	thermal resistance junction to heatsink			0.62	K/W

## Source-Drain Diode

Symbol	Definitions	Conditions	Ratings		
			min.	typ.	max.
$V_{SD}$	forward voltage drop	$I_F = 40 \text{ A}; V_{GS} = -5 \text{ V}$	$T_{VJ} = 25^\circ\text{C}$	5.2	V
			$T_{VJ} = 150^\circ\text{C}$	4.6	V
$t_{rr}$	reverse recovery time	$V_{GS} = -5 \text{ V}; I_F = 40 \text{ A}; V_R = 800 \text{ V}$ Mosfet gate drive: $V_{GS} = -5 / 20 \text{ V}; R_G = 10 \Omega$	$T_{VJ} = 25^\circ\text{C}$	16	ns
$Q_{RM}$	reverse recovery charge (intrinsic diode)			330	nC
$I_{RM}$	max. reverse recovery current			35	A
$dl_F/dt$	current slew rate			4800	A/ $\mu\text{s}$
$t_{rr}$	reverse recovery time	$V_{GS} = -5 \text{ V}; I_F = 40 \text{ A}; V_R = 800 \text{ V}$ Mosfet gate drive: $V_{GS} = -5 / 20 \text{ V}; R_G = 10 \Omega$	$T_{VJ} = 150^\circ\text{C}$	26	ns
$Q_{RM}$	reverse recovery charge (intrinsic diode)			810	nC
$I_{RM}$	max. reverse recovery current			45	A
$dl_F/dt$	current slew rate			4600	A/ $\mu\text{s}$

Note: When using SiC Body Diode the maximum recommended  $V_{GS} = -5\text{V}$

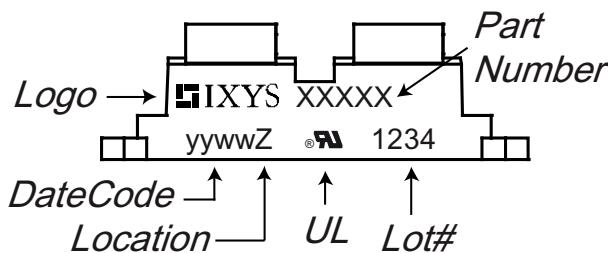
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Package Outlines SOT-227B (minibloc)			Ratings			
Symbol	Definitions	Conditions	min.	typ.	max.	Unit
$I_{RMS}$	<i>RMS current</i>	per terminal			100	A
$T_{stg}$	<i>storage temperature</i>		-40		150	°C
$T_{op}$	<i>operation temperature</i>		-40		150	°C
$T_{VJ}$	<i>virtual junction temperature</i>		-40		175	°C
<b>Weight</b>				30		g
$M_D$	<i>mounting torque</i> <sup>1)</sup>	screws to heatsink terminal connection screws			1.5 1.3	Nm Nm
$d_{Spp}$ $d_{Spb}$	<i>creepage distance on surface</i>	terminal to terminal terminal to backside	10.5 8.5			mm mm
$d_{App}$ $d_{Appb}$	<i>striking distance through air</i>	terminal to terminal terminal to backside	3.2 6.8			mm mm
$V_{ISOL}$	<i>isolation voltage</i>	$I_{ISOL} \leq 1 \text{ mA}; 50/60 \text{ Hz}$	$t = 1 \text{ sec.}$ $t = 1 \text{ minute}$	3000 2500		V V
$C_P$	<i>coupling capacity per switch</i>	between drain and back side metallization with gate and source shorted		42		pF

<sup>1)</sup>further information see application note IXAN0073 on  
[www.ixys.com/TechnicalSupport/appnotes.aspx](http://www.ixys.com/TechnicalSupport/appnotes.aspx) (General / Isolation, Mounting, Soldering, Cooling)

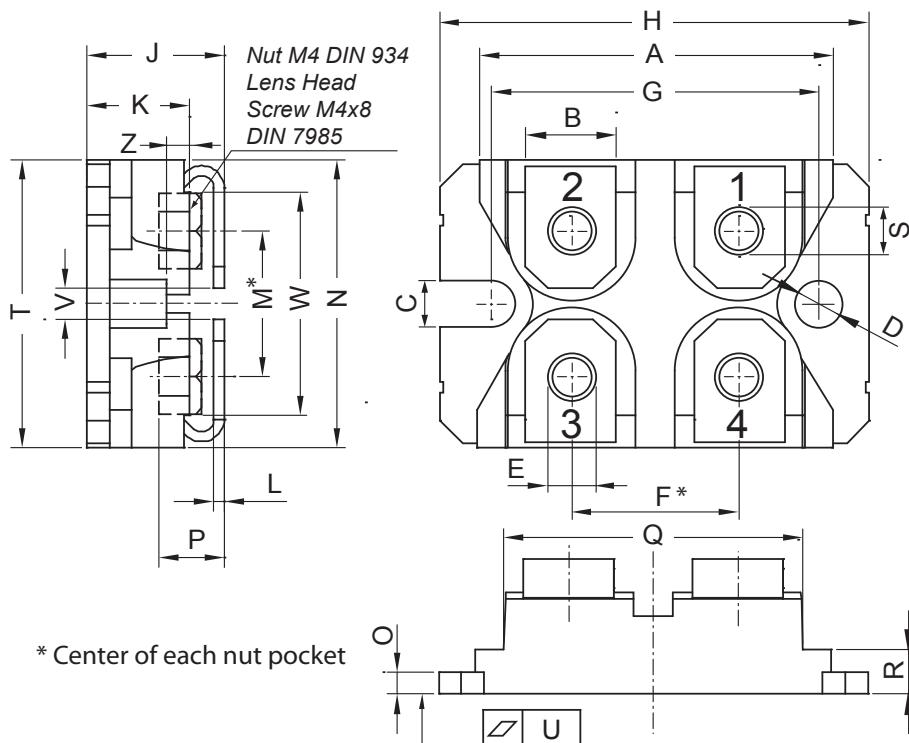
## Product Marking



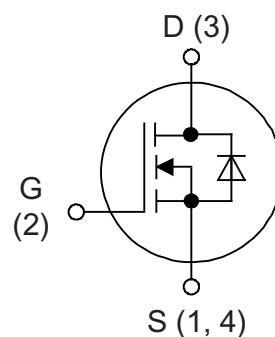
Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	IXFN50N120SiC	IXFN50N120SiC	Tube	10	IXFN50N120SiC



## Outlines SOT-227B (minibloc)

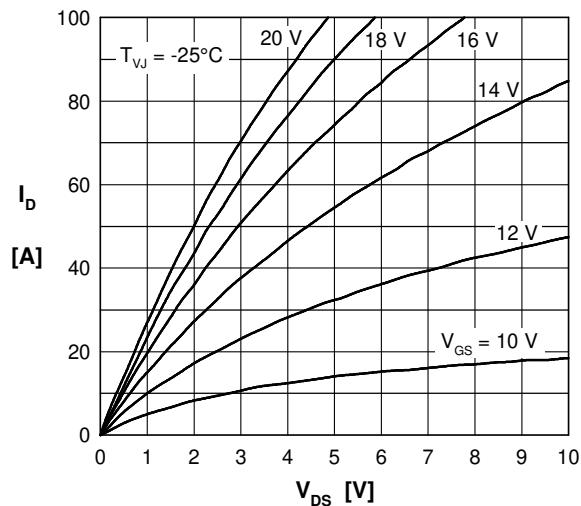
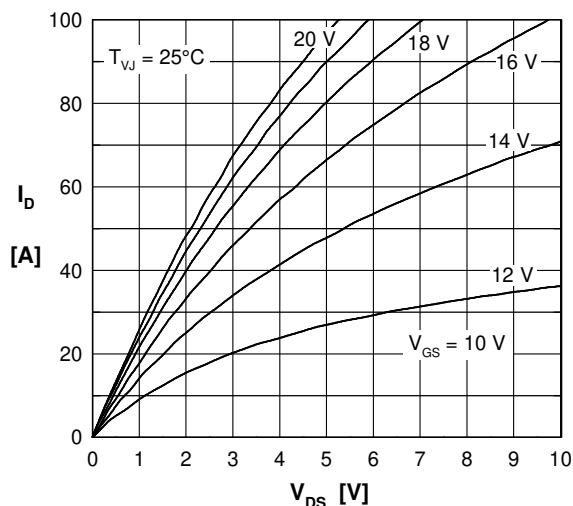
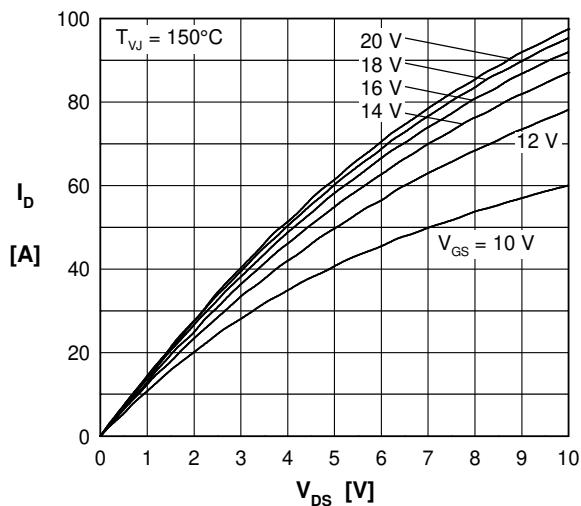
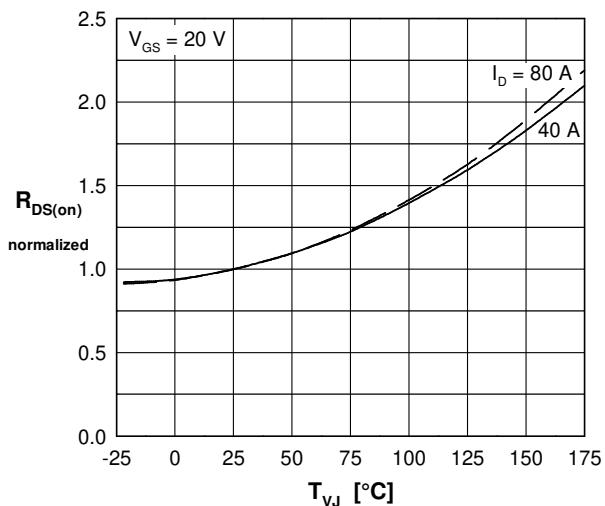
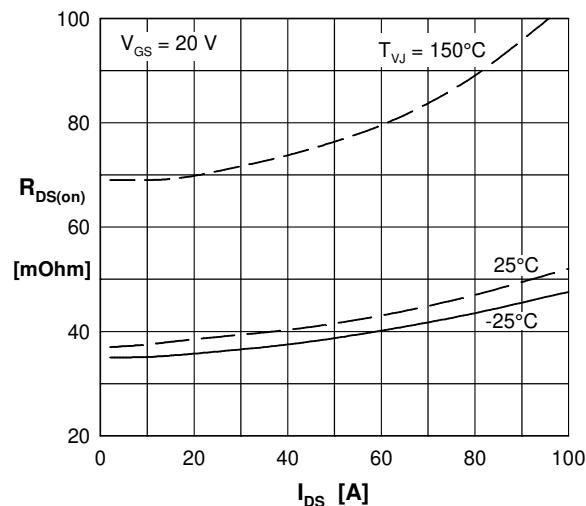
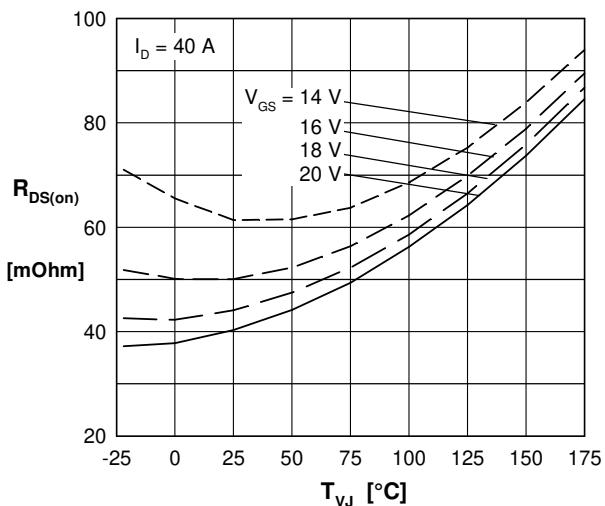


Dim.	Millimeter		Inches	
	min	max	min	max
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	37.80	38.23	1.488	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.74	0.84	0.029	0.033
M	12.50	13.10	0.492	0.516
N	25.15	25.42	0.990	1.001
O	1.95	2.13	0.077	0.084
P	4.95	6.20	0.195	0.244
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.167
S	4.55	4.85	0.179	0.191
T	24.59	25.25	0.968	0.994
U	-0.05	0.10	-0.002	0.004
V	3.20	5.50	0.126	0.217
W	19.81	21.08	0.780	0.830
Z	2.50	2.70	0.098	0.106





## Curves

Fig. 1 Typical output characteristics ( $-25^\circ\text{C}$ )Fig. 2 Typical output characteristics ( $25^\circ\text{C}$ )Fig. 3 Typical output characteristics ( $150^\circ\text{C}$ )Fig. 4  $R_{DS(on)}$  normalized vs. junction temperature  $T_{VJ}$ Fig. 5  $R_{DS(on)}$  versus drain currentFig. 6  $R_{DS(on)}$  versus junction temperature  $T_{VJ}$ 

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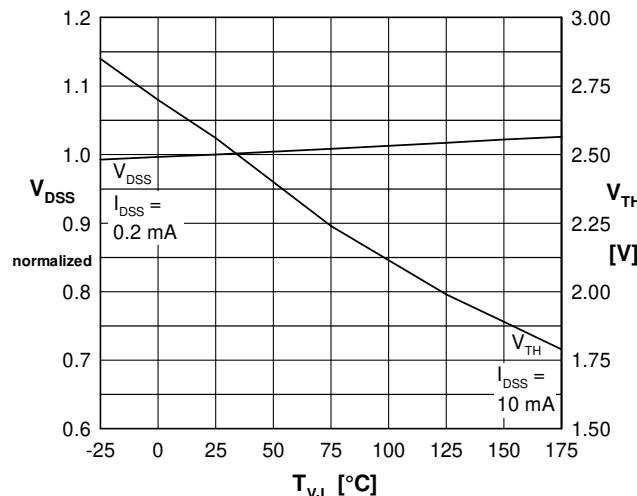
**Curves**


Fig. 7 Norm. breakdown  $V_{DSS}$  & threshold voltage  $V_{TH}$  versus junction temperature  $T_{VJ}$

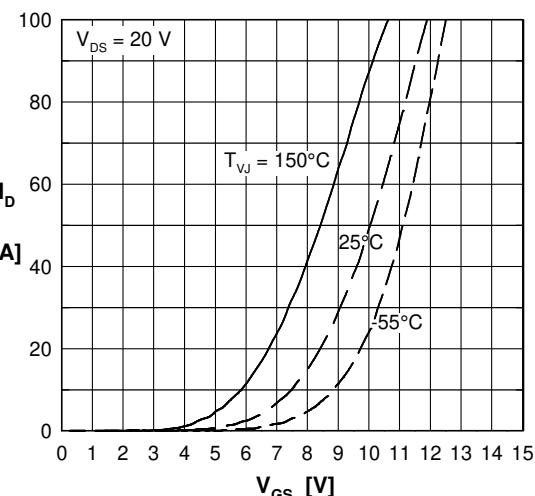


Fig. 8 Typical transfer characteristics

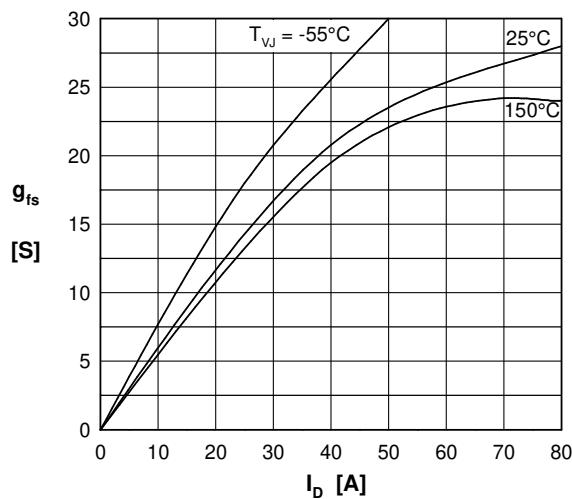


Fig. 9 Typical forward transconductance

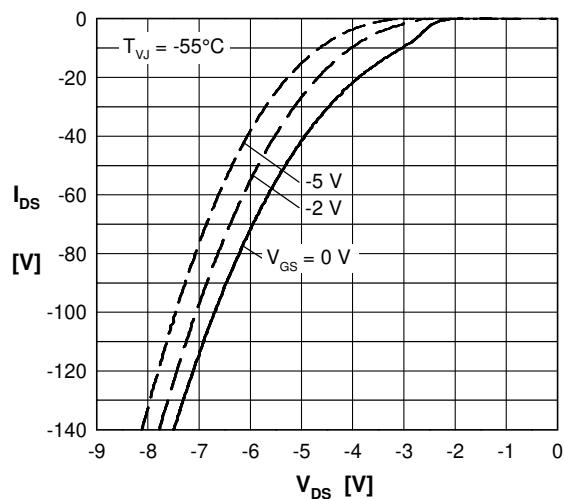


Fig. 10 Forward voltage drop of intrinsic diode versus  $V_{DS}$  measured at  $-55^{\circ}\text{C}$

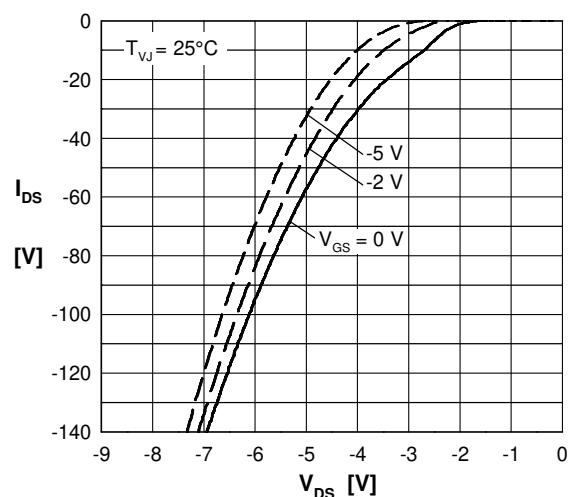


Fig. 11 Forward voltage drop of intrinsic diode versus  $V_{DS}$  measured at  $25^{\circ}\text{C}$

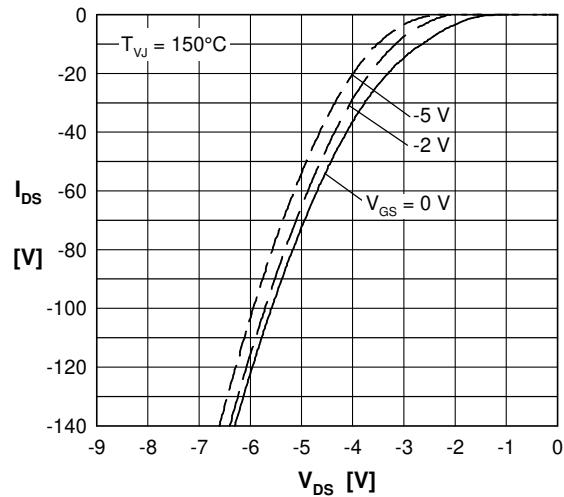


Fig. 12 Forward voltage drop of intrinsic diode versus  $V_{DS}$  measured at  $150^{\circ}\text{C}$



## Curves

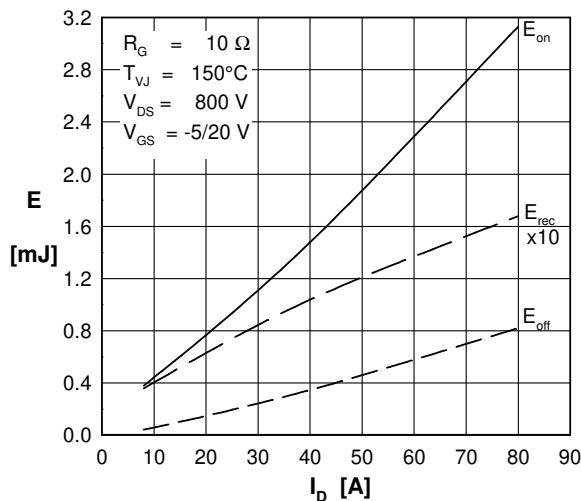


Fig. 13 Typical switching energy versus drain current

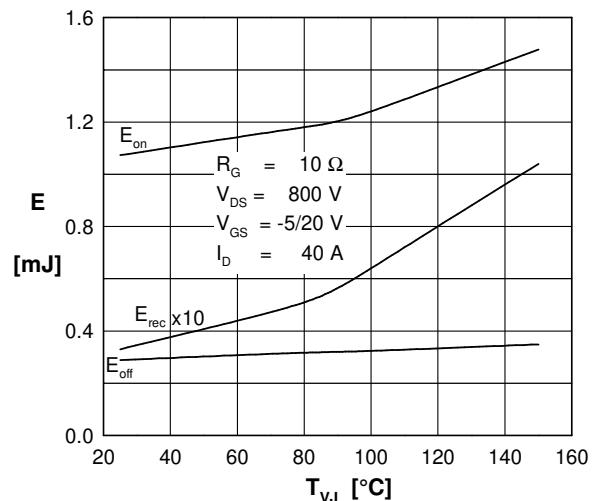


Fig. 14 Typical switching energy versus temperature

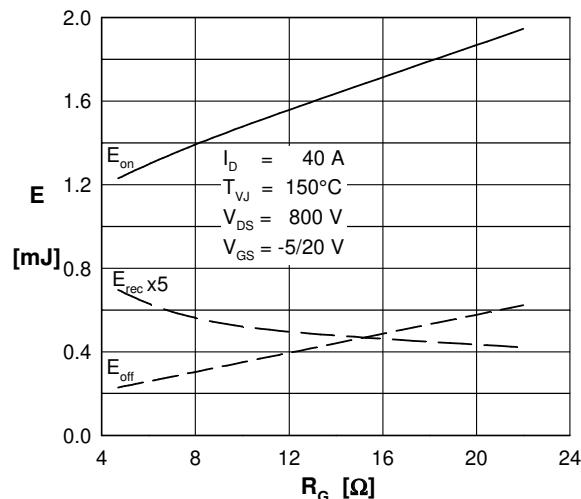


Fig. 15 Typical switching energy versus external gate resistor

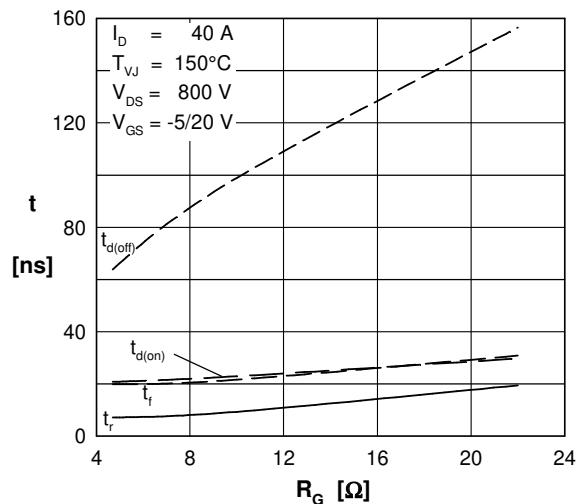


Fig. 16 Typical switching time versus external gate resistor

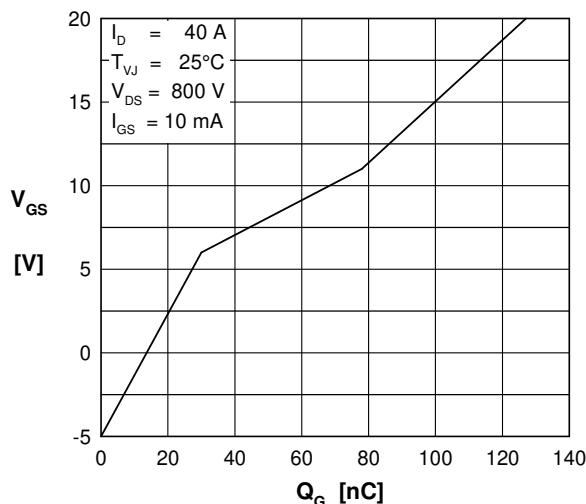


Fig. 17 Typical turn on gate charge, trendline

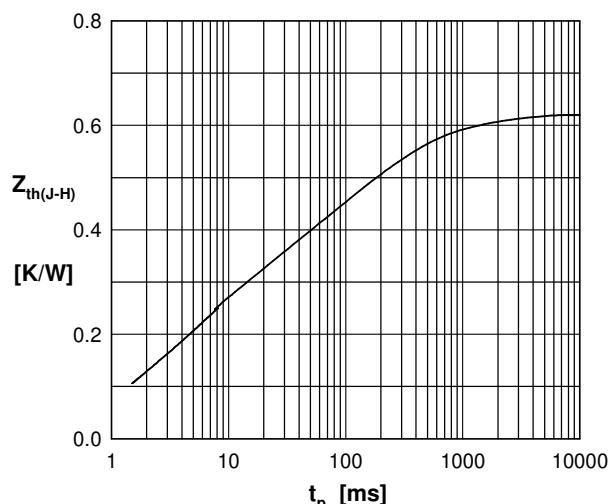


Fig. 18 Typical transient thermal impedance